



# Kick Interference to the Curb: Tackle ICP-OES Applications with Ease

Maura Rury, Regional Marketing Manager  
NEMC 2017

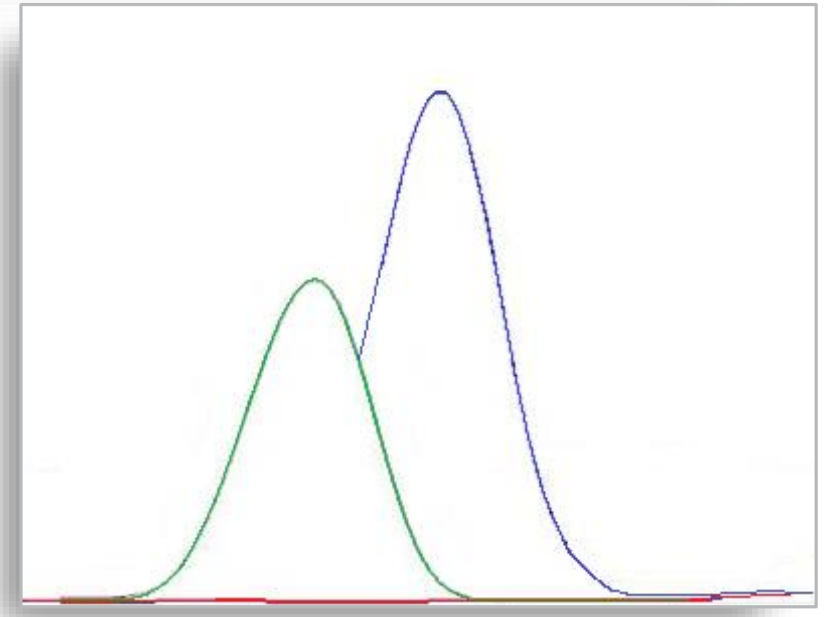
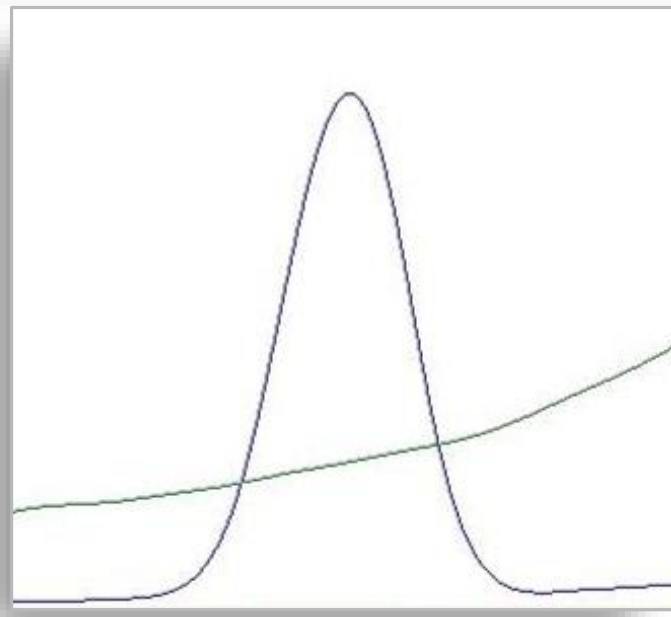
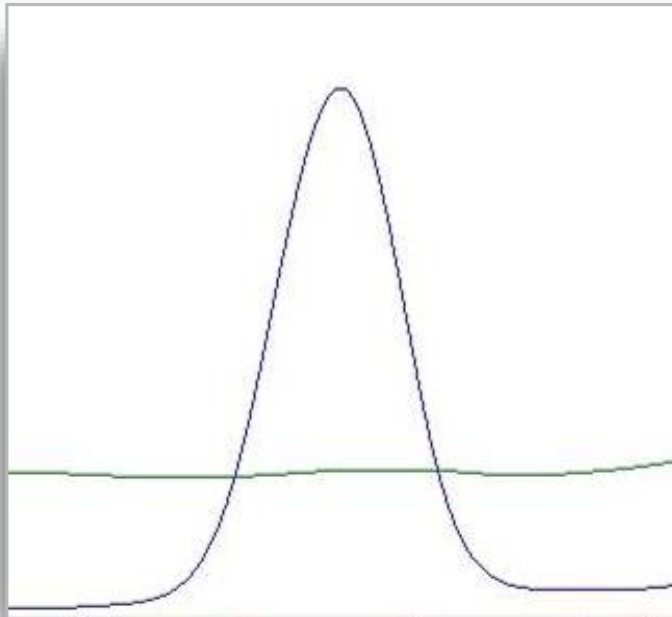
## What are spectral interferences?

- Produced when emission spectra from matrix components overlap with those of the analyte/s
- They result from interactions between components in the sample and the sample matrix
- The severity of the interferences is dependent on the analyte wavelengths being used



## Examples

- Background shift (flat, raised or lowered baseline)
- Background shift (sloped baseline)
- Partial peak overlap
- Full, complete peak overlap



Do you need to correct for these?

- Spectral interferences alter the magnitude of the signal that reaches the detector
- The magnitude of the signal is related to the concentration present in the sample
- If the signal increases/decreases as a result of an interference, the instrument will produce an incorrect concentration



**Correcting for interferences – probably a good idea!**



## Use One or More Correction (IEC) Factors

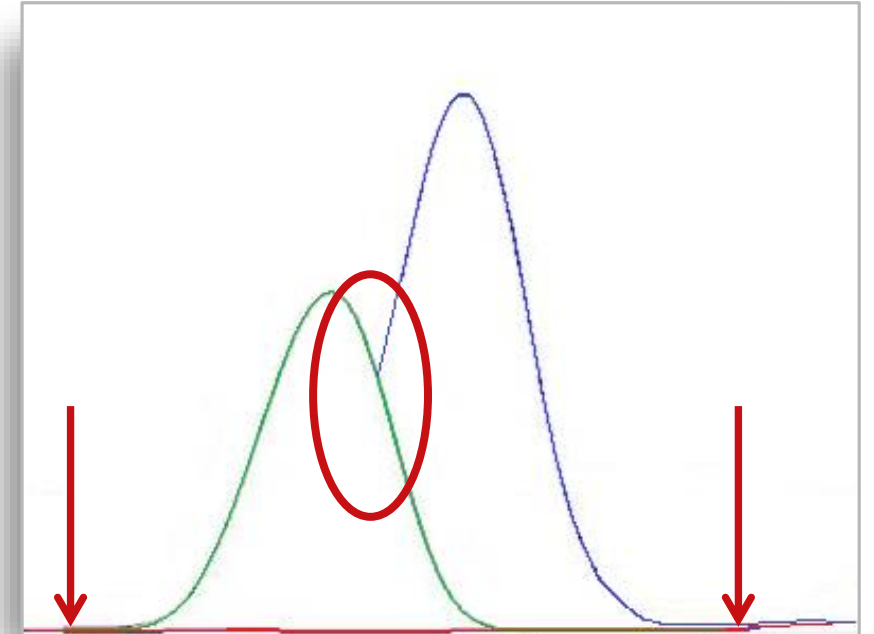
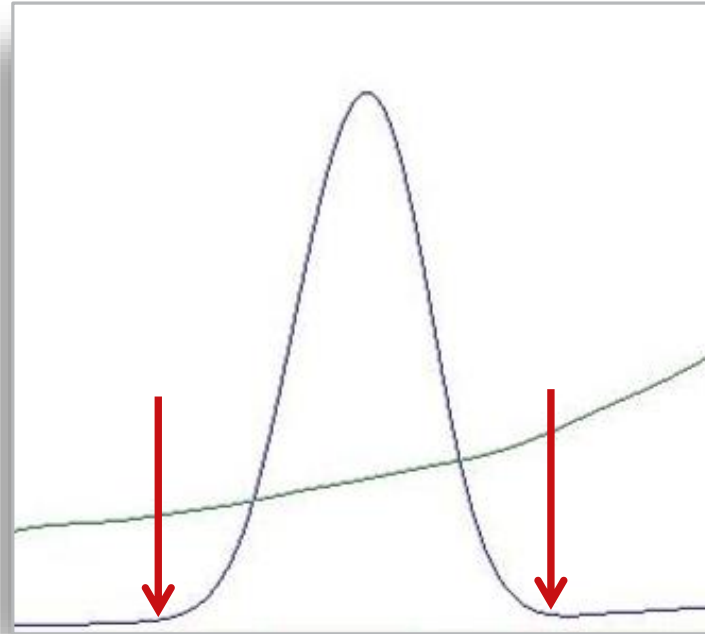
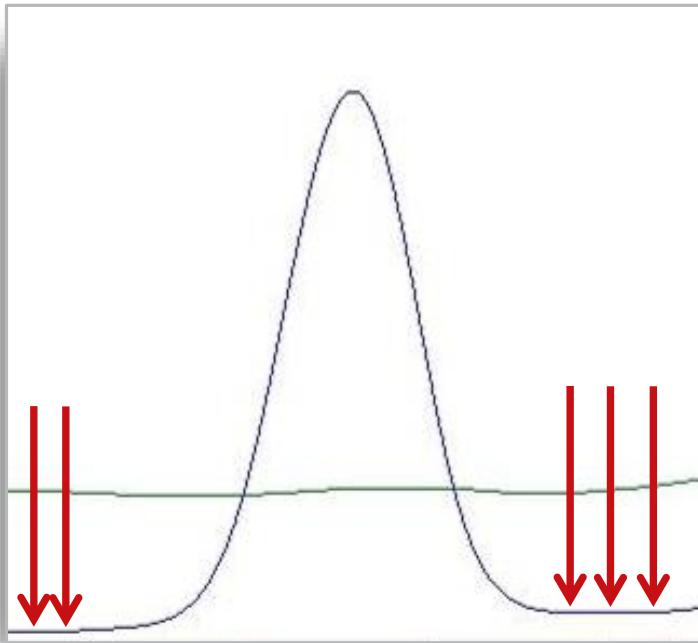
- Just follow these simple steps:
  - Identify all elements that have interferences
  - Identify all elements that are causing interferences
  - Use carefully-prepared solutions to allow the instrument to measure the spectral overlap and calculate an accurate IEC factor
  - Repeat process for each interference that must be corrected
  - Re-calculate all IEC factors if any conditions change (plasma parameters, sample matrix, analyte mixture)



**Isn't there another way to correct for interferences?**

## Use Careful Background Point Selection

- Background correction should mimic shape of background emission
- Avoid overcorrection or correction on a nearby emission peak



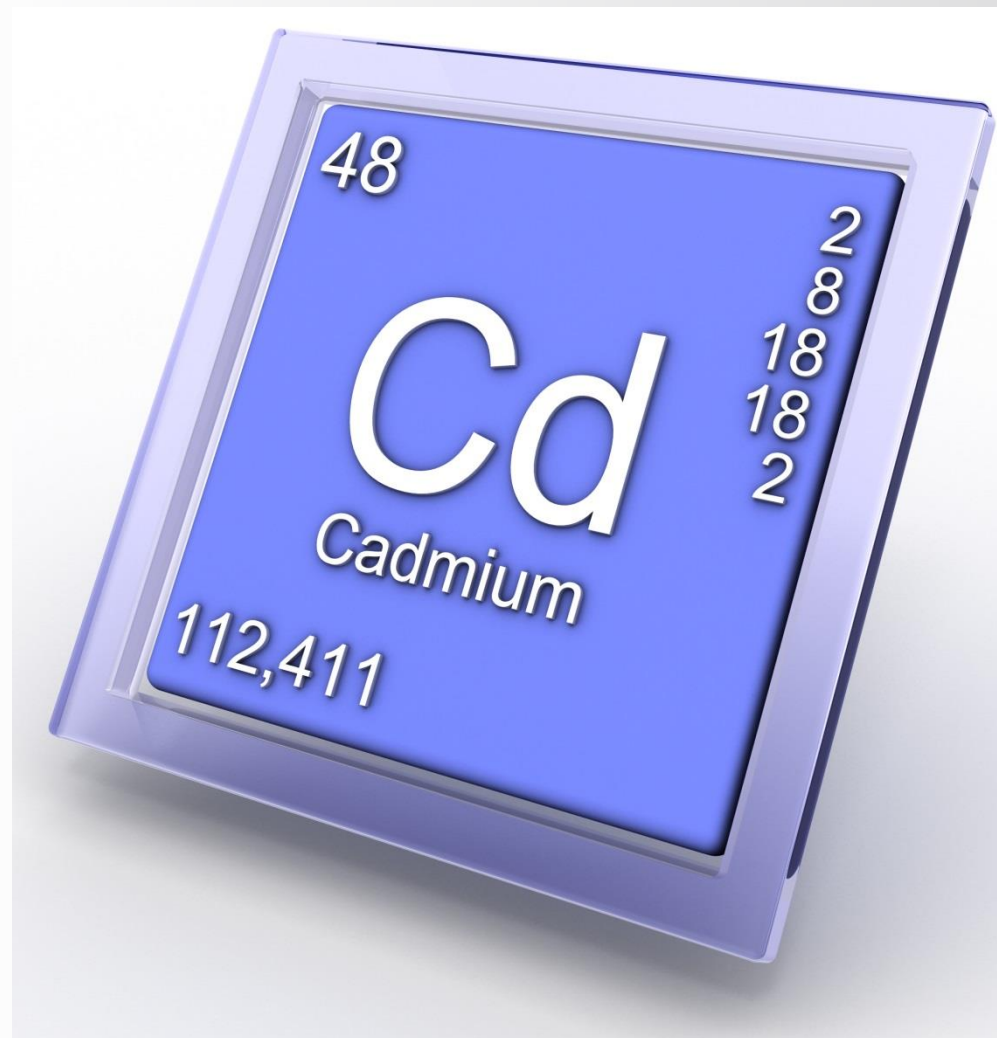
## Use Careful Wavelength Selection

- Careful wavelength selection – ideally, interference free!
- Element Finder plug-in for Thermo Scientific™ Qtegra™ ISDS Software
  - Automatically selects interference-free wavelengths
  - Eliminates interferences before you know they exist



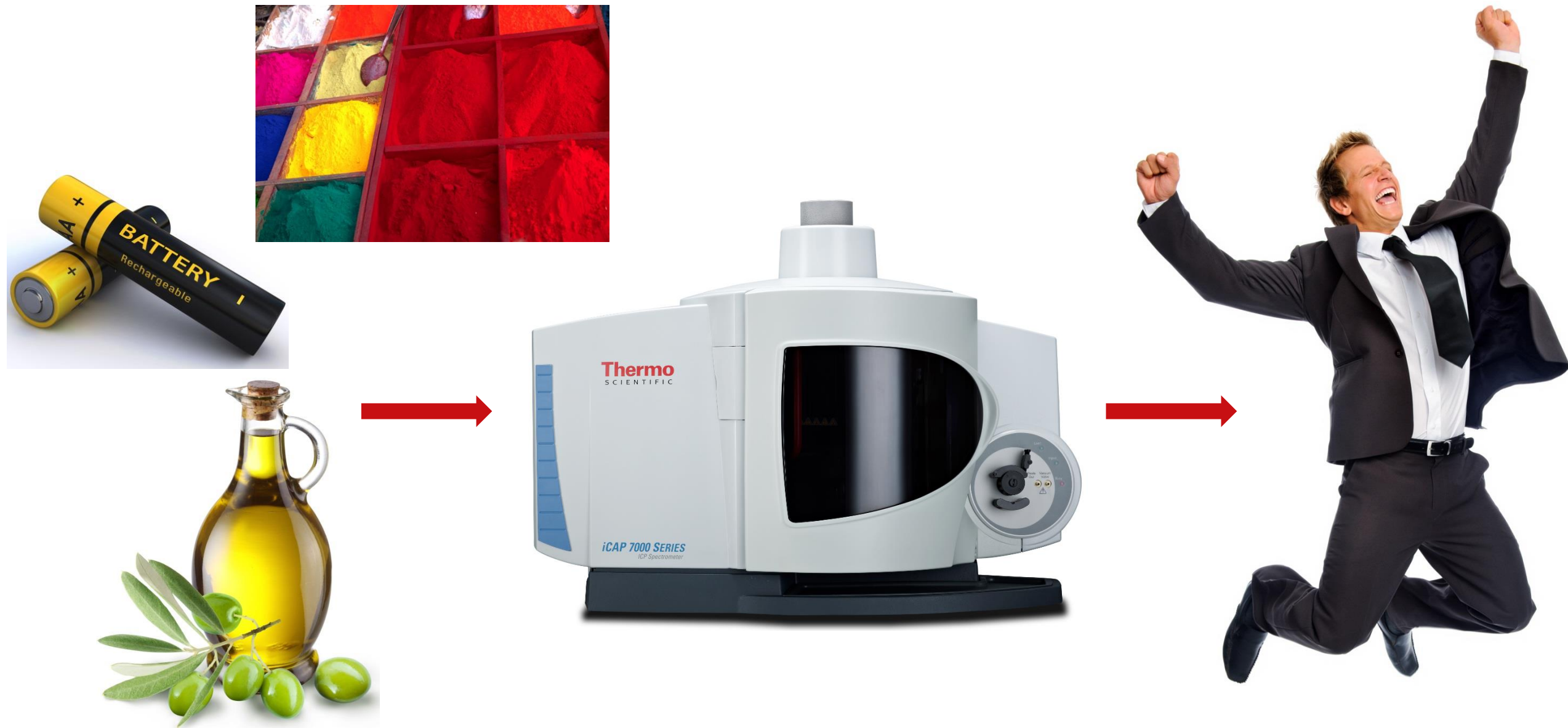
## Analysis of Cd

- Where do we want it?
  - Rechargeable NiCd batteries
  - Paint pigments (“cadmium yellow” or “cadmium red”)
  - He-Cd lasers
  - Corrosion-resistant plating materials
- Where don't we want it?
  - Airborne particles
  - Drinking water
  - Fruits/vegetables grown in Cd-contaminated soil
  - Rice grown in Cd-contaminated fields
  - Food oils





# Analysis of Cd – Theory



# Analysis of Cd – Reality



**Non-linear calibration  
curve?!?!**

**125% Recovery!**

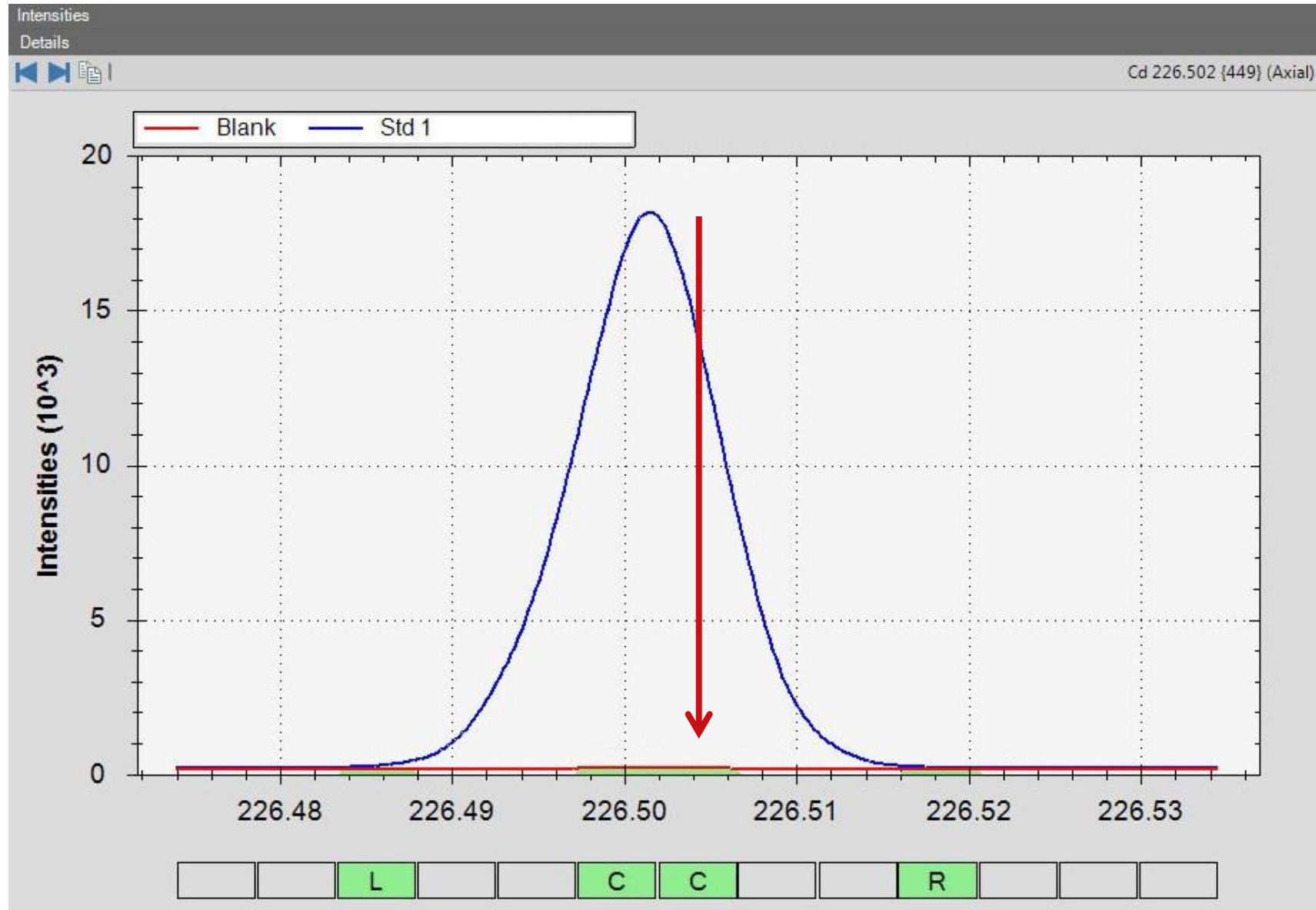
**1.5 ppm?  
That's too high!**

**QC standards  
don't pass?!?!**



# Analysis of Cd – What Happened?

- Wavelength Scan of a Multi-Element Standard
- Single-Element Standard Containing Fe



# Addressing Interference on Cd



## Element Finder



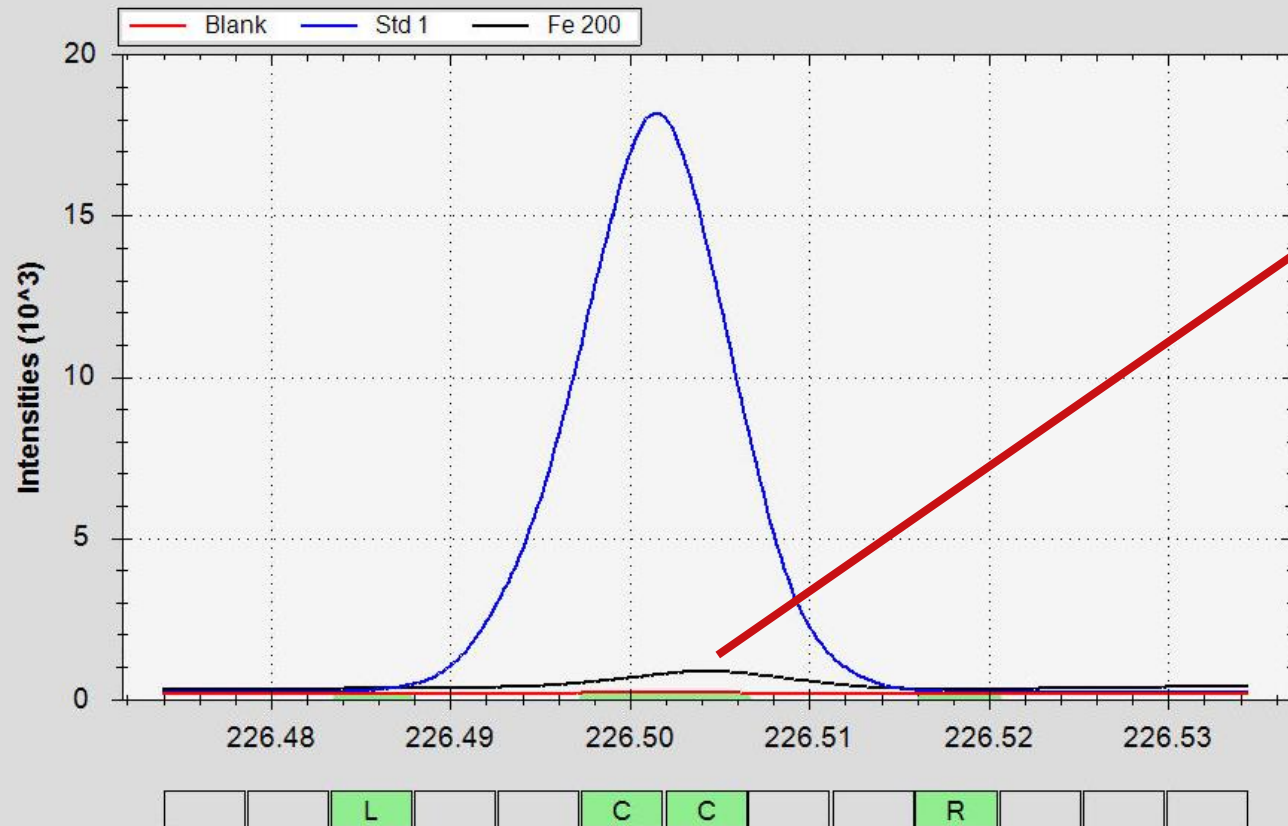
Use this method to determine the best combination of lines based on your element selection

Intensities

Details



Cd 226.502 {449} (Axial)



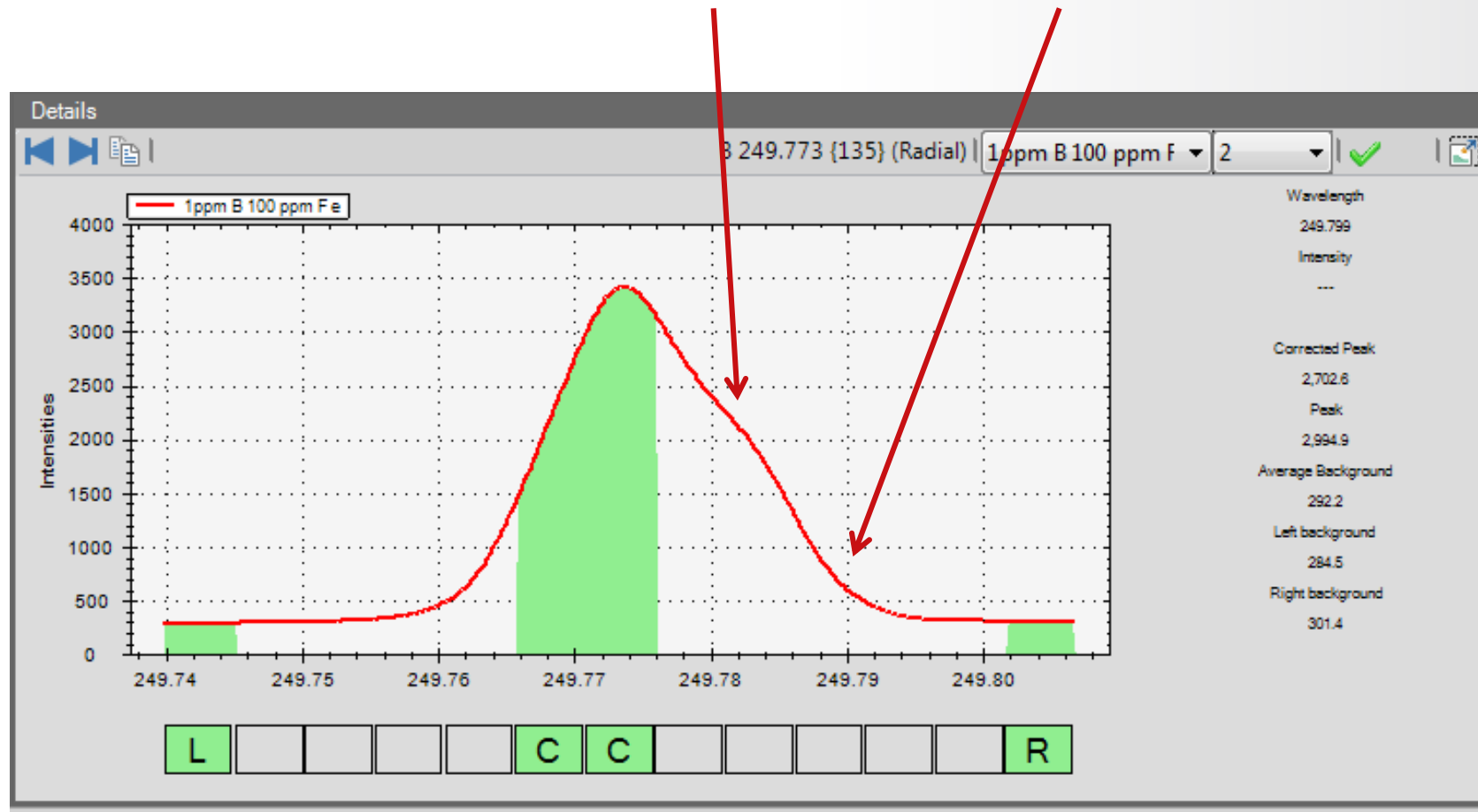
## Here's How Element Finder Helps:

1. Hey! You have an interference!
2. It's probably from Fe!
3. What do you want to do about it?
  1. Calculate an IEC? – not recommended!
  2. Find an alternative wavelength? Let me help you!
4. Cd has a strong emission wavelength at 214 nm; Fe doesn't emit there – try that one!



# Another Spectral Interference Example

- Analysis of B in a high Fe sample matrix – asymmetric peak for boron at 249.773 nm
- Clear interference on boron peak (visible at 249.780 nm and 249.790 nm)



## Analyze three solutions:

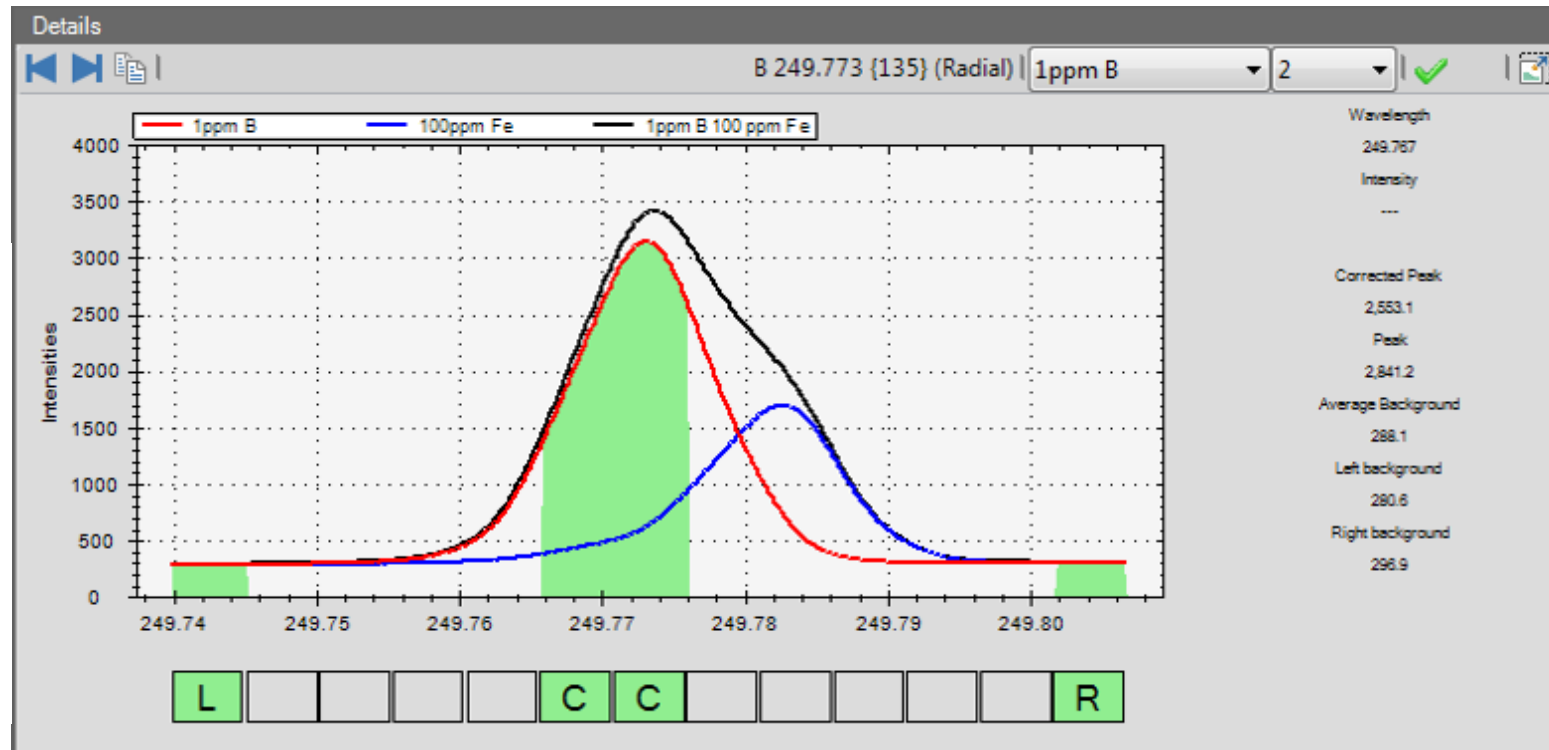
1. The sample
2. A single element solution of the analyte at the concentration in the sample
3. A single element solution of the suspected interference at the concentration in the sample
  - If this is not the interfering analyte, further analysis might be needed to determine this

## Then

- Measure the interference to calculate a correction factor

**OR**

- Select an alternative wavelength that is free from interferences

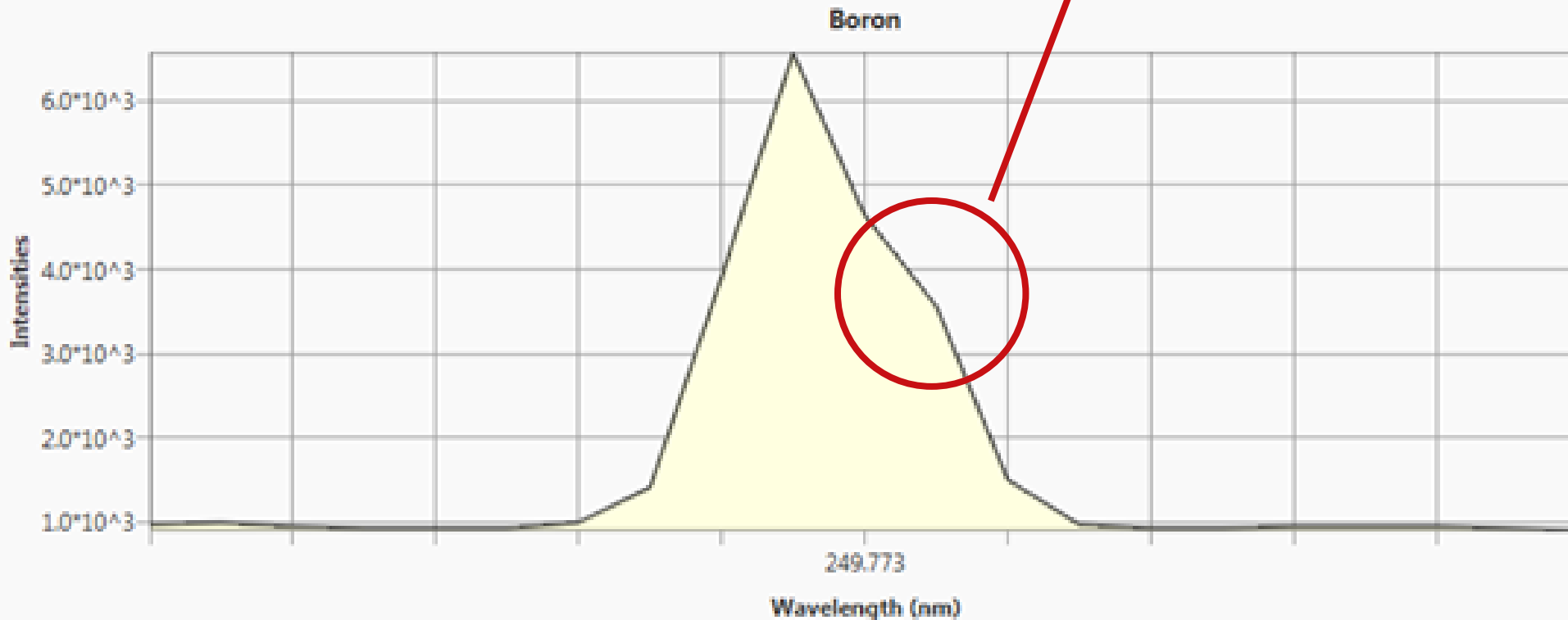


# Automatic Interference Identification

- Boron interference automatically detected and identified!

Wavelengths suggested for Analyte Elements that are suited to your analysis

5	Wavelength	Order	Intensity	Preference	Available for analysis	Measure Mode	Remarks
<b>B</b> Boron Analyte	249.773	135	4,000,000	Automatic	No	Radial	Interference with: Fe, 249.782; Interfer
	249.678	135	2,000,000	Automatic	No	Radial	Interference with: Fe, 249.653; Interfer
	208.959	461	1,500,000	Automatic	Yes	Radial	
	208.893	461	750,000	Automatic	No	Radial	Interference with: Fe, 208.412;
	182.641	484	660,000	Automatic	No	Radial	
	182.591	484	290,000	Automatic	No	Radial	
	181.837	485	73,000	Automatic	No	Radial	



Available for analysis?

**NO!**

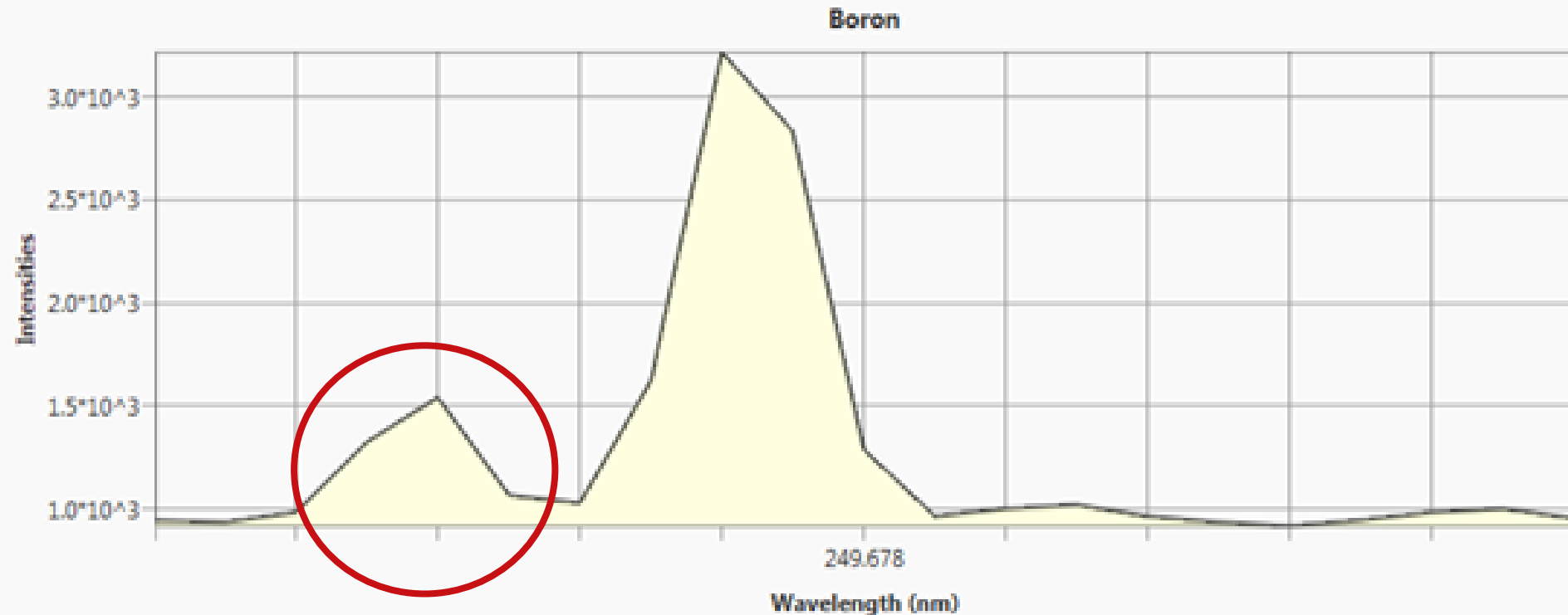
# Automatic Identification – Additional Interferences Found!

Wavelengths suggested for Analyte Elements that are suited to your analysis

Wavelength	Order	Intensity	Preference	Available for analysis	Measure Mode	Remarks
249.773	135	4,000,000	Automatic	No	Radial	Interference with: Fe, 249.782; Interfer
249.678	135	2,000,000	Automatic	No	Radial	Interference with: Fe, 249.653; Interfer
208.959	461	1,500,000	Automatic	Yes	Radial	
208.893	461	750,000	Automatic	No	Radial	Interference with: Fe, 208.412;
182.641	484	660,000	Automatic	No	Radial	
182.591	484	290,000	Automatic	No	Radial	
181.837	485	73,000	Automatic	No	Radial	

Available for analysis?

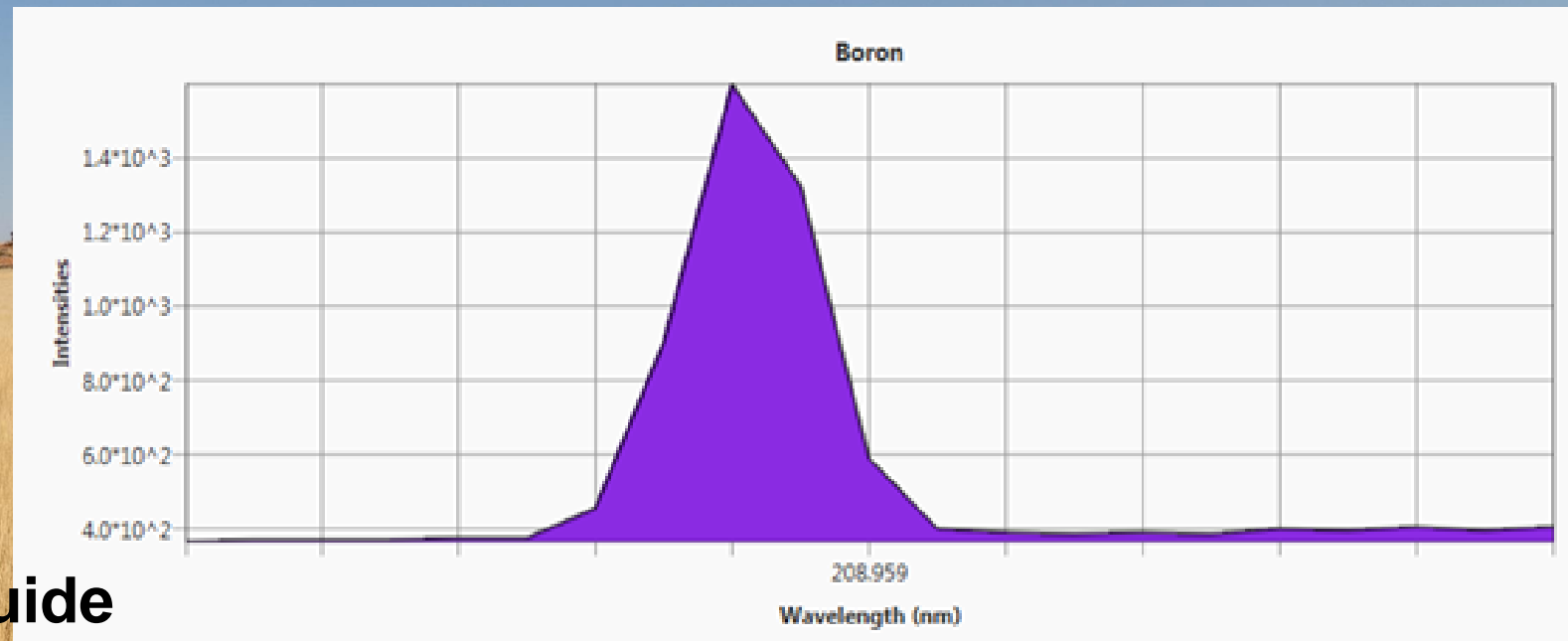
~~NO!~~  
YES!





# Automatic Interference Identification

Wavelengths suggested for Analyte Elements that are suited to your analysis								
5	Wavelength	Order	Intensity	Preference	Available for analysis	Measure Mode	Remarks	
<b>B</b> Boron Analyte	249.773	135	4,000,000	Automatic	No	Radial	Interference with: Fe, 249.782; Interfer	
	249.678	135	2,000,000	Automatic	No	Radial	Interference with: Fe, 249.653; Interfer	
	208.959	461	1,500,000	Automatic	Yes	Radial		
	208.893	461	750,000	Automatic	No	Radial	Interference with: Fe, 208.412;	
	182.641	484	660,000	Automatic	No	Radial		
	182.591	484	290,000	Automatic	No	Radial		
	181.837	485	73,000	Automatic	No	Radial		



Let Element Finder be your guide

## Trace Elements in Pentanol

- Multiple interference challenges

1. Physical

- Differences in nebulization and/or transport efficiency between the standards and samples

2. Chemical

- Differences between the behavior of standards and samples when in the plasma
  - Easily ionized element (EIE) effects
  - Plasma loading

3. Spectral

- Atomic emission overlaps from other elements in the sample
- Molecular emission from solvent



## Trace Elements in Pentanol

- Multiple interference challenges

### 1. Physical

- Differences in nebulization and/or transport efficiency between the standards and samples

### 2. Chemical

- Differences between the behavior of standards and samples when in the plasma
  - Easily ionized element (EIE) effects
  - Plasma loading

### 3. Spectral



**Element Finder**

- Atomic emission overlaps from other elements in the sample
- Molecular emission from solvent

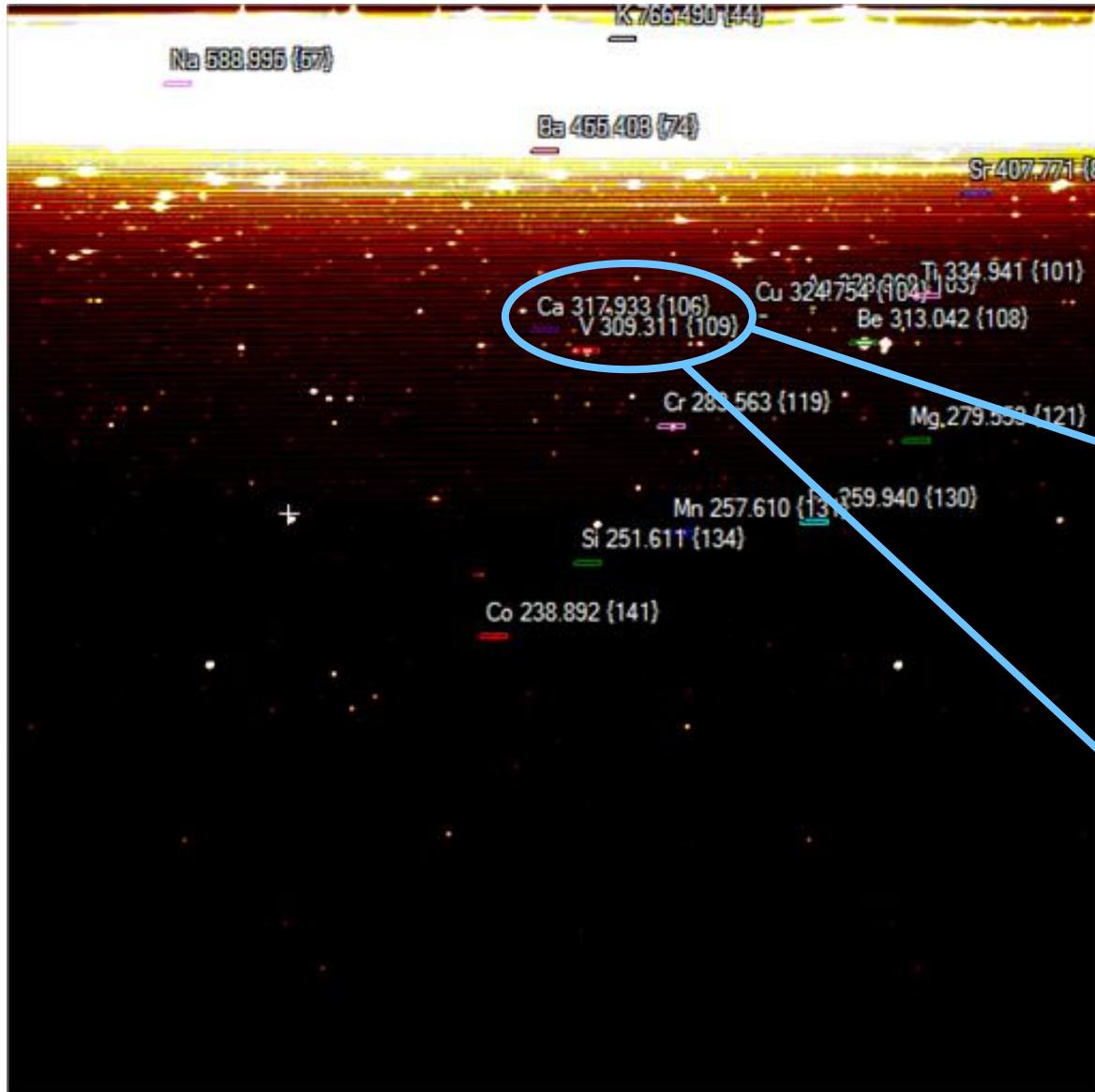
Matrix match standards  
to samples

Use an internal  
standard

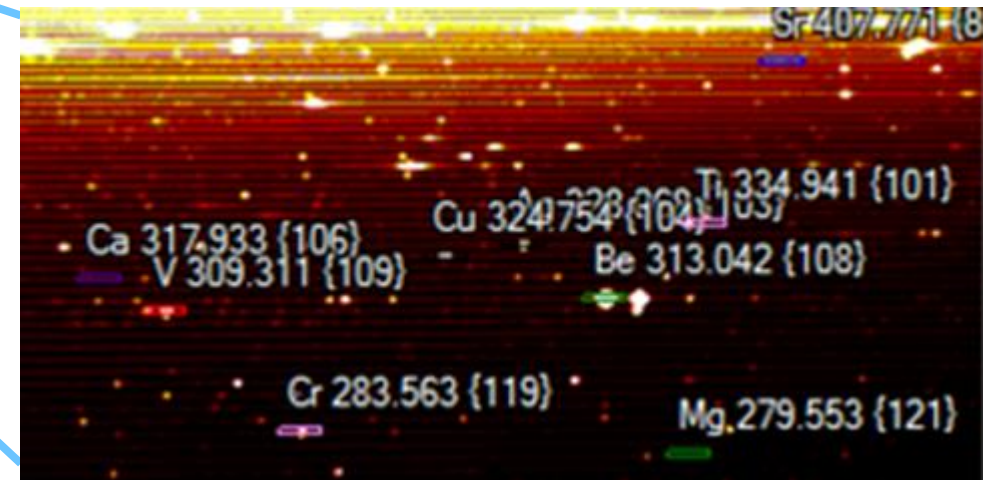
Carefully select  
sample introduction

Reduce sample  
uptake to reduce  
matrix loading

# Full Frame of Pentanol Sample



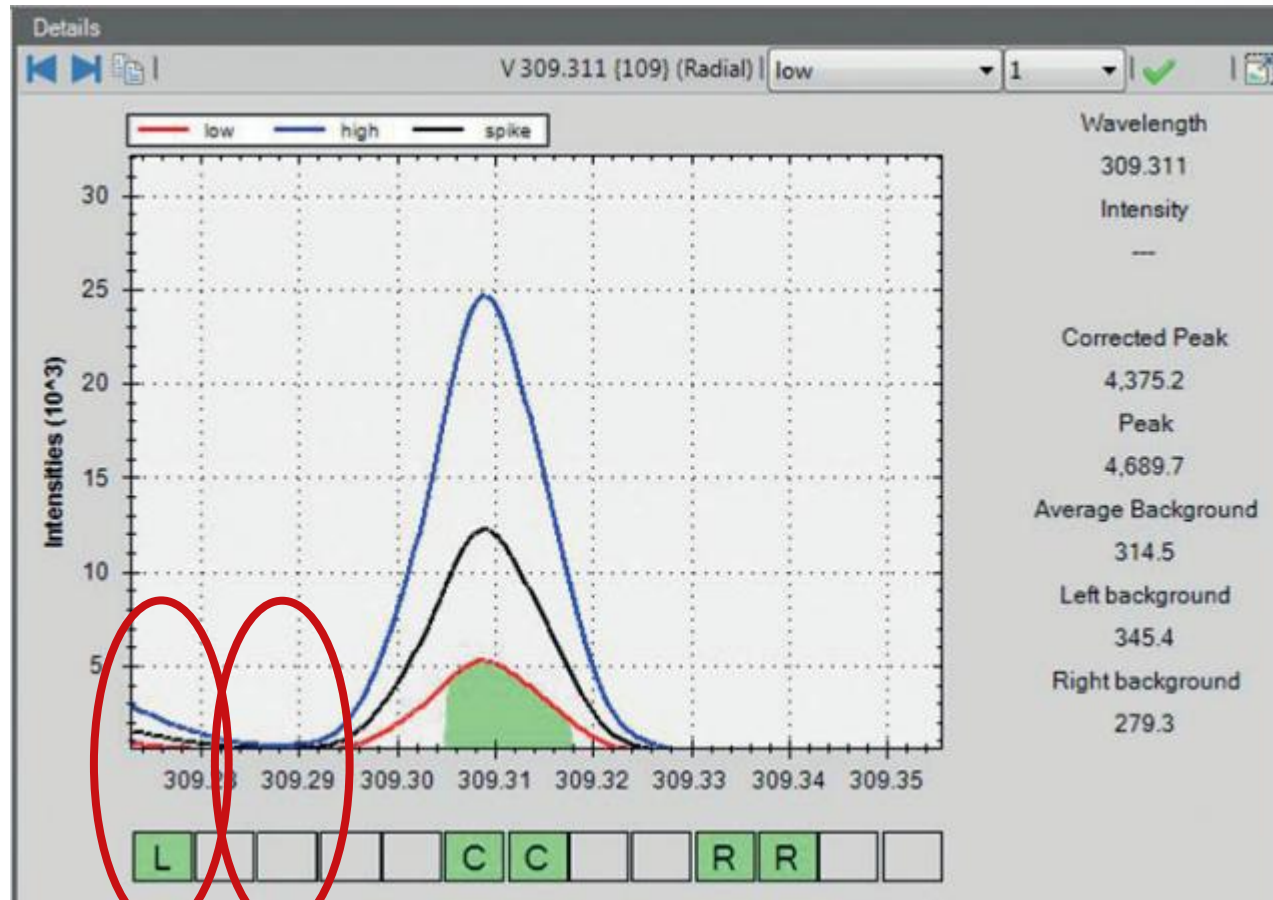
- Emission from other analytes
- Emission from sample contaminants
- Molecular emission from solvent (CO, CO<sub>2</sub>, CN)





# Spectral Background

- Vanadium wavelength scan



Possible Interferences

Interferences for V 309.311 (109) (Ra			
Symbol	Line	State	Intensity
Cd	309.234	II	100000
Sc	309.249	II	112500
Pu	309.259	II	10000
Al	309.271	I	600000
Na	309.273	II	6188
Nd	309.273	II	10000
Al	309.284	I	0
Sc	309.288	I	18750
Nd	309.292	II	0
Mg	309.298	I	277778
Mg	309.299	I	2037037
U	309.301	II	8000
Th	309.305	II	12000
V	309.311	II	2500000
Tm	309.311	II	25000
Er	309.314	II	18000
V	309.324	I	833
Mn	309.335	I	5185
U	309.337		2500
Ar	309.34	II	3571
W	309.35	I	1500
Os	309.359	I	9310

# Pentanol Results

- Successful tactics to address interferences
- Results: Good precision and accuracy, and spike recoveries ~100%

Element and Wavelength (nm)	View	Spike Concentration (mg kg <sup>-1</sup> )	Measured Spike Concentration (mg kg <sup>-1</sup> )	Spike Recovery (%)	RSD on three Replicates of the Spike (%)	MDL (µg kg <sup>-1</sup> )
Ag 328.068	Radial	2.47	2.45	99.2	1.6	3.5
Al 167.079	Axial	2.47	2.82	114.2	0.2	1.4
As 189.042	Axial	2.49	2.58	103.6	0.2	7.6
Ba 455.403	Radial	2.47	2.53	102.4	1.8	0.3
Ca 393.366	Radial	2.47	2.46	99.6	1.9	0.2
Cd 214.438	Axial	2.47	2.69	108.9	0.3	0.3
Cr 267.716	Radial	2.47	2.48	100.4	1.6	4.8
Cu 324.754	Radial	2.47	2.41	97.6	2.0	2.4
Fe 238.204	Radial	2.47	2.50	101.2	1.6	4.8
Hg 184.950	Axial	2.48	2.59	104.4	0.6	2.6
K 766.490	Radial	2.47	2.41	97.6	2.4	55
V 309.311	Radial	2.47	2.46	99.6	1.7	2.1

# Kick Interference to the Curb for Successful ICP-OES Results

- Thoughtful method development will ensure that physical, chemical and spectral interferences are identified and corrected
  - Wavelength scans and full frame images (captured in seconds) will help illustrate nearby emission from other analytes and sample matrix components and the solvent
  - Background shifts and nearby spectral interferences can often be addressed with careful background correction
  - When background correction is insufficient on its own:
    - Spend your valuable time and lose productivity calculating IEC factors
- OR**
- Let Element Finder identify possible interferences and automatically select alternative wavelengths

**Imagine** Automated Method Development!

New Element Finder plug-in for Qtegra Intelligent Scientific Data Solution software with ICP-OES analysis.

**Find your elements** [thermofisher.com/ICP-OES](http://thermofisher.com/ICP-OES)

